

## PATENT APPLICATION

Sheet 1 of 1

FORM PTO-1449

LIST OF PATENTS AND PUBLICATIONS FOR  
APPLICANT'S INFORMATION DISCLOSURE  
STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO.

200207083-1

APPLICATION NO.

10/600,875

CONFIRMATION NO.

APPLICANT

Blaine Stackhouse et al.

FILING DATE

Herewith

GROUP

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
DN	1A	6,256,241 B1	Jul. 3, 2001	Mehalel	
DN	1B	6,501,692 B1	Dec. 31, 2002	Melanson et al.	
	1C				
	1D				
	1E				
	1F				
	1G				
	1H				
	1I				
	1J				
	1K				

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	1L					
	1M					
	1N					
	1O					
	1P					

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

DN	1Q	Sanjay Sengupta et al., "Defect-Based Test: A Key Enabler for Successful Migration to Structural Test," Intel Technology Journal, Q1, 1999, pp. 1-14.
	1R	
	1S	

EXAMINER

DATE CONSIDERED

7/15/04